Author index

Abendroth, H., 461
Adair, I. V., 181
Adams, F. D., 410
Alfrey, T., Jr., 103
Archbold, E., 410, 427
Armstrong, G. W. D., 181
Asundi, A., 432, 433
Austin, S., 165, 248

Baracat, W. A., 270, 313
Bar-Ziv, E., 191
Basehorse, M. L., 301, 324, 326
Bayer, M. H., 164, 166, 246, 254, 313, 316, 317
Beidermann, K., 453
Boone, P., 432
Born, M., 14, 16, 40, 43, 46, 61, 63, 64, 196
Bradley, W. A., 182
Brčič, V., 388
Brooks, R. E., 344, 410
Brown, I. C., 324
Brown, G. W., 344, 387
Burch, J. M., 162, 236, 401, 410, 431, 432
Butters, J. N., 410, 453, 454, 462

Carré, P., 488
Cesarz, W., 172
Chen, X. L., 393, 473
Chiang, F. P., 157, 179, 182, 227, 243, 263, 432, 433
Clutterbuck, M., 121
Coker, E. G., 16, 61, 64, 116
Conley, E. G., 433, 435, 436
Cookson, T. J., 462
Creath, K., 393, 477, 481, 483, 490
Czarnek, R., 280

Dainty, J. C., 410
Dally, J. W., 64, 77, 101, 128, 143, 147, 151, 157
Daniel, I. M., 103, 263
Dantu, M., 147, 167
Der Hovanesian, J., 184, 187, 189, 388, 410
DeBacker, L., 432
Duffy, D., 410, 428
Durelli, A., 148, 153, 263

Eggers, H., 461
Ek, L., 453
Eliaisson, B., 410
Ennos, A. E., 365, 395, 400, 401, 402, 410, 427, 440, 451
Erf, R. K., 387
Erisman, E. R., 128

Falco, R., 432
Filon, L. N. G., 16, 61, 64, 116
Forno, C., 162, 236, 237, 431, 432
Fourney, M. E., 388
Frocht, M. M., 64, 77, 91, 114

Gabor, D., 343, 344
Garbuny, M., 16, 117
Glatt, I., 191
Author index

Goodman, J. W., 196, 346, 395, 397, 399, 400
Greivenkamp, C. J., 485
Groh, G., 410
Guild, G., 227, 273
Guo, Y., 333, 338

Haines, K. A., 344
Han, B., 157, 270, 304, 313, 323, 333, 338
Harding, K., 189
Hariharan, P., 346
Harris, F. C., 60, 62, 77, 91, 140
Harris, J. S., 189
Haskell, R. E., 48, 196, 217, 346
Heffinger, L. O., 344, 410
Hermann, R., 165, 166, 246, 248
Hildebrand, B. P., 344
Hagemoen, K., 453, 462, 463
Holister, G. S., 163, 246, 248
Horman, M. H., 344
Hu, C., 410
Hu, H. Z., 481
Hung, Y. Y., 184, 187, 189, 410
Hyzer, J. B., 334, 339

Ifft, P. G., 157, 270, 304, 313, 323

James, J. F., 275
Jessop, H. T., 60, 62, 77, 91, 140
Jones, R., 346, 374, 393, 395, 400, 404, 405, 410, 440, 444, 445, 447, 448, 453, 454, 472

Kafri, O., 191
Kao, T. Y., 182
Kerber, R. C., 263
Keren, E., 191
Khentan, R. P., 187, 188
Köpf, U., 410

Leek, J., 172
Leendertz, J., 410, 447, 453
Leith, E. N., 344
Li, D., 433

Lichtenberg, F. K., 182
Lökberg, O. J., 453, 462, 463
Lu, B., 461
Luxmoore, A. R., 163, 165, 166, 246, 248

Macovské, A., 453
Maddux, G. E., 410
McDonach, A., 270, 313
McKelvie, J., 174, 270, 313, 324
MacLaughlin, T. F., 227
Mesmer, G., 98
Moga, P. J., 190, 191
Morse, S., 148
Mottier, F., 410

Nokes, J., 457, 461, 473
Oster, G., 148

Paleebut, S., 242, 263, 264, 432, 433
Parks, V. J., 148, 153, 157, 179, 184, 427
Peiffer, J., 165, 246, 432, 433
Perry, S. H., 324
Peters, W. H., 374
Pollard, H. C., 462
Powell, R. L., 344, 388

Radke, R., 165, 246, 432, 433
Ramsey, S. D., 453
Ranson, E. F., 374
Richard, T. S., 174
Riley, W. F., 64, 77, 101, 143, 147, 148, 151, 157
Rowlands, R. E., 174

Schaefer, L. F., 453
Shagam, R. N., 481
Sharpe, W. N., Jr., 45
Shurtleff, W. A., 25, 28
Sikarskie, D., 313
Slettemoen, G. A., 465
Smith, H. M., 346, 374, 376
Sternberg, R. S., 275
Stone, F. T., 165, 248
Straka, P., 246
Stroke, G. W., 275, 346
Sulaimana, R., 242, 254
Sutton, M. A., 374
Takasaki, H., 179
Taylor, C. E., 410
Taylor, D., 410
Theocaris, P. S., 103, 148, 151, 179
Tiziani, H., 410
Tokarski, J. M. J., 410
Tolansky, S., 40, 43, 46, 47
Upatnieks, J., 344

Vable, M., 313
Van Wijk, M. C., 181
Varner, J. R., 389
Voloshin, A. S., 174
Walker, C., 270, 313, 323, 324, 334, 339
Wasserman, M., 148
Waters, J. P., 346, 374
Whittier, J. G., 263
Wolf, E., 14, 16, 40, 43, 46, 61, 63, 64, 196
Wolf, H., 64, 77
Wuerker, R. F., 344
Wyant, J. C., 481, 488
Wykes, C., 346, 374, 393, 395, 400, 404, 405, 410, 440, 444, 445, 447, 448, 453, 454, 472
Yang, X., 461
Zandman, F., 163, 165
Zwerling, C., 148
Subject index

absolute retardation, 59
Airy disc, 398; see also diffraction by clear aperture; laser speckle analogs, 130
coloring paper analogy, 131
electro-optic fluid, 131
membrane analogy, 130
aperture, see diffraction by clear aperture
birefringence, 59
dielectric tensor, 61
Fresnel ellipsoid, 62
principal axes of, 60, 63
principal values of, 61
refractive index ellipsoid, 63
birefringence in materials, 64, 102
circular polariscope, 75
coherent optical data processing, see spatial filtering
complex amplitude, 23
complex variables, 22
computer data reduction, see moire with optical processing
creep and relaxation tests, 104
creep coefficients, optical and mechanical, 115
diffraction at an aperture
arbitrary aperture, 217
basic concept, 37
Fourier transform, 37
see also diffraction by clear aperture; diffraction theory; holography
diffraction by clear aperture, 207
Airy disc, 209–10
holography and moire, 212
large aperture case, 211–12
misuse of Fraunhofer equation, 211
sinc function, 209
small aperture case, 210–11
transmittance function, 208
diffraction by grating, 212
orders, 215
transmittance function, 213
see also moire interferometry; speckle photography
diffraction by hologram, see holography
diffraction by lens, 215
Fresnel integral equations, 217–19
optical Fourier transform, 219–21
scaling factor, 217
diffraction by superimposed gratings, 227
Fourier transform model, 233
fringe formation, 230
higher orders, 230
moire pattern, 229
and sensitivity multiplication in moire, 233
sine grating, 227
whole-field, 229–30
diffraction theory, 195
Fourier transform, 206, 219–21
Fraunhofer approximations, 203, 206–7
Fraunhofer diffraction integral, 206–7
Fraunhofer equation, 206
Fresnel approximation, 203–5
Fresnel integral, 205
Fresnel–Kirchhoff formula, 201
Helmholtz equation, 197
Helmholtz–Kirchhoff formula, 200
Huygens–Fresnel construction, 195
Kirchhoff assumptions, 200
Kirchhoff integral, 197–201
plane wavefront case, 201
Subject index

problem identification, 195
Stokes theorem, 197
transparency in aperture, 201
see also diffraction by clear aperture;
diffraction by grating; diffraction by lens; diffusion by superimposed gratings; pinhole spatial filter; spatial filtering
dispersion, 116
of birefringence, 117
normalized dispersion of birefringence, 118
normalized retardation, 117
optical, 116
Doppler effect, 48
electromagnetic spectrum, 19
electronic holography, see electronic speckle pattern interferometry
electronic speckle pattern interferometry
advantages, 470–1
basic concept, 454
Bessel function, 461
camera, 456
camera resolution, 464
correlation fringe formation, 457
depth of field, 472
dynamic measurement, 463
error sources, 473
frequency response of monitor, 465
fringe brightness, 459–61
fringes by addition, 459–60
fringes by subtraction, 457–9
fringe visibility optimization, 467, 469
generic system, 454
light intensity optimization, 463–4
limitations, 471–3
in nondestructive inspection, 473
object size, 471
optical setups, 455–6
phase relations, 458–61
practical system, 474
resolution for smooth reference beam, 467
resolution for two speckle beams, 466
resolution limitations summary, 469
sample results, 458
sensitivity, 471
spatial resolution, 464–70
speckle size, 464
surface condition, 472
time-average fringes, 461–3
vibration measurement, 461–3
video system, 456
see also phase shifting interferometry;
speckle interferometry
embedded grating, see moire with optical processing
enhanced moire, see moire with optical processing
ESPI, see electronic speckle pattern interferometry; phase shifting interferometry
extraordinary ray, 62
Fourier optical processing, 227; see also
diffraction by lens; spatial filtering
Fourier optics, see diffraction theory
Fourier transform, see diffraction theory
fractional fringe order
Babinet–Soleil compensator, 141
birefringent compensator, 141
phase shifting, 140, 477
Senarmont method, 138–40
summary of methods, 135
Tardy method, 136
Fresnel diffraction integral, see diffraction theory
fringe visibility, 35
geometric moire
creating gratings and grids, 163
direct superimposition, 159
double exposure, 161–2
fringe formation, 148
fringe order-displacement-rotation, 148
in-plane motion and strain, 155
observing techniques, 159
optical superimposition, 162–3
pitch mismatch, 179
rotation effects, 169
sensitivity, 173
sensitivity improvement, 174
sensitivity multiplication, 161
slope, contour, out-of-plane displacement, 179
strain rosette, see moire strain rosette
two-dimensional strain analysis, 166
see also moire, moire pitch mismatch,
projection moire, reflection moire, shadow moire
grating photography, 161
with slotted apertures, 161, 175
see also slotted apertures
harmonic grating, see diffraction by grating
harmonic wave, 18
holographic interferometry
  basic concepts, 345
  basic rules, 374
  Bessel function, 363
  contour fringes, 360
  contour mapping, 389
  dependence on viewing and illumination angles, 369
  displacement, in-plane, 368
  displacement, out-of-plane, 364, 368
  double exposure, 356
  fringe interpretation, 357, 360, 363, 364
  fringe localization, 370–2
  frozen fringe method, 356
  holographic photoelasticity, 388
  line-of-sight displacement, 364
  live fringe method, 358
  qualitative interpretation, 363–4
  real-time method, 358
  sensitivity vector, 365–70
  small-angle approximation, 369
  small viewing aperture, 371
  time-average method, 360
  see also holography
holographic interferometry techniques
  developing in place, 385
  double exposure procedures, 384–5
  in nondestructive testing, 387
  optical setups, see holography
  real-time plateholder, 386
  real-time procedure, 385–6
  refractive index change in contouring, 389
  time-average procedure, 386
  two wavelengths for contouring, 389
  wet plate holder, 386
holography
  basic ideas, 344–5
  carrier fringes, 355
  conjugate beam, 352
  diffraction theory, 353
  equations, 348–51
  Fraunhofer integral, 353
  history, 343
  hologram as diffraction grating, 354–5
  hologram as transmittance filter, 350–3
  holographic lens, 355
  image reconstruction equations, 349–54
  images, 351–2
interference of reference and object beams, 347
primary beam, 351
producing a hologram, 346
pseudoscopic image, 352
reconstruction as diffraction process, 353
recording equations, 349
recording geometry, 347
see also holographic interferometry
holography techniques
  films and plates, 382–3t
  holographic platform, 375
  image plane holography, 390
  multiple object beams, 378
  optical setups, 376–8
  phase objects, 378
  photoresists, 384
  recording media, 381–4
  recording procedure, 379–81
  spatial filter, 377
  tables, 375
  thermoplastic recording media, 384
  viewing procedure, 379–81
Huygens construction, 44, 271
index of refraction: correction for, in three-dimensional measurements, see moire with optical processing
intensity of light, 24
interference
  of collinear waves, 31
  constructive, 32
  destructive, 32
  fringes, 34
  fringe spacing, 36
  phase–irradiance equations, 34
  of two plane waves, 32–6
interference of two beams, see holography; interference; moire interferometry
interferometer, generic, 38
interferometric measurement of birefringence, 66
common retardation, 72
fringe patterns, 71
see also photoelasticity; photoelasticity equations
interferometric strain gage, 45
interferometry, classical, 40
irradiance, 24
Subject index

isochromatic fringes, 72, 92
fringe order, 95
interpretation, 95–6
recording, 92
isoclinic fringes, 72, 88
interpretation, 90
recording, 88
Kirchhoff integral, see diffraction theory
laser Doppler interferometry, 47
beat frequency, 51
interpretation of signal, 51
laser speckle
brightness distribution, 399–400
coherent and incoherent mixing of, 401–2
coherent combinations of, 400
decorrelation by in-plane rotation, 407–8
decorrelation by in-plane translation, 406–7
decorrelation by out-of-plane tilt, 407
decorrelation by out-of-plane translation, 405–6
decorrelation criteria, 405
fully developed pattern, 399
Gaussian speckle, 399
memory loss, 404
objective speckle, 397
phase decorrelation, 404
polarization effects, 402
probability functions, 400–2
sensitivity vector, 408
signature of surface, 403
speckle correlation metrology, 403–4
speckle decorrelation, 403–4
speckle effect, 395–6
speckle photography, 403
speckle size, 397–9
subjective speckle, 397–9
lens as Fourier analyzer, see diffraction by lens
light, 13
quantum model, 14
wave model, 13
linear polariscope, 66
mathematical approaches, 21
Fourier transforms, 22
see also complex amplitude; matrix methods
matrix methods, 25
Jones calculus, 27
Mueller calculus, 25
Stokes vector, 25, 27
Maxwell’s equations, 14
Michelson interferometer, 46
model similarity and scaling
basic concepts, 99
Buckingham’s theorem, 122
material properties, 120
Mitchell’s conditions, 121
multiply connected regions, 120
scaling law, 123
simply connected regions, 120
size and load scaling, 122
moire
equations, 150–1
fringe-displacement-strain, 148–52
fringes, 148
optical Fourier processor, 235
parametric description, 148
rigid body motion measurement, 155
whole field analysis, 152
see also diffraction by superimposed gratings; geometric moire; moire interferometry; moire with optical processing; slotted apertures
moire effect, 147
moire fringe patterns by optical processing, 234
moire fringes, 152
moire in interior of specimen, see moire with optical processing
moire interferometer
adjustment, 319
construction, 314
design objectives, 313
mirror orientation, 317
optical scheme, 315
three-axis six-beam apparatus, 315
moire interferometry
analysis of two-dimensional field, 301
concepts, 269
definitions, 273
deformation of specimen grating, 282
diffraction by grating, 271
frequency of specimen grating, 281
fringe formation, 287
fringe order–displacement relation, 289
general grating equation, 273
geometry of interferometer, 280
grating equations, 272, 273, 277
Subject index

moire interferometry—continued
  Huygens construction, see Huygens construction
  interference and diffraction, 269
  pitch mismatch, 304–11
  pitch mismatch in strained specimen, 307
  pitch mismatch in undeformed specimen, 304
  shear strain determination, 302
  sign convention, 278
  six-beam three-axis layout, 281
  strain rosette, 302
  three-dimensional grating equations, 277
  two-beam interference in, 278
  virtual grating, 270

moire interferometry fringes
  of 45°-displacement, 295
  of x-displacement, 284
  of y-displacement, 295
  produced by in-plane rotation, 283, 296
  produced by normal strain, 285
  produced by normal strain, \( \epsilon_x \), 295
  produced by normal strain, \( \epsilon_y \), 289
  produced by normal strain, \( \epsilon_y \), 298
  produced by out-of-plane rotation, 293, 301
  produced by shear strain, \( \gamma_{xy} \), 291
  produced by shear strain, \( \gamma_{x'y'} \), 298
  rotation effects, 312

moire interferometry techniques
  data reduction, 331
  experimental methods, 323
  fringe recording, 328
  grating replication, 328
  grid transfer method, 324
  sample results, 331–9
  specimen gratings, 323
  transfer molding, 324

moire of moire, 153

moire with optical processing advantages, 241
  computer data reduction, 259
  digitizing fringes, 257–9
  fringe data reduction, 253
  fringe patterns, 251
  grating focus, 250
  gratings, master and submaster, 243–6
  gratings for specimens, 246; see also photoresists
  multiple embedded gratings, 263
  normal strain parallel to axis, 257
  normal strain perpendicular to axis, 259
  numerical data reduction, 256
  optical processing, 252
  photography of specimen gratings, 249
  procedure summary, 242
  refractive index correction, 264
  sample results, 262
  spatial filtering, 252
  technique outline, 242
  three-dimensional analysis, 263
  moire pitch mismatch, 175; see also moire interferometry, moire with optical processing
  moire strain analysis, concept, 156
  moire strain rosette, 167, 171, 172
  momentarily linearly elastic, 105

Newton’s rings, 40
  equation, 42
  noncoherent light speckle, see white light speckle photography

optical spatial filtering, see moire with optical processing; spatial filtering ordinary ray, 62

path length difference, 38, 44

phase measurement interferometry, see phase shifting interferometry

phase shifting interferometry
  algorithms, 483–90
  background, 477
  basic concepts, 478–82
  Carré technique, 488–9
  detector output plot, 480
  displacement from phase, 491
  four-step technique, 488
  integrating bucket technique, 484
  intensity–phase relations, 485–7
  interferometric experiment, 479
  modulation optimization, 483–4
  phase measurement techniques, comparison, 489
  phase shift concept, 480–1
  phase shift methods, 481–3
  phase-stepping technique, 484
  phase unwrapping, 489–90
  piezoelectric transducer, 481–2
  precision, 481
  sampling problem, 483
  setup, 482
  three-step technique, 487
phase stepping interferometry, see phase shifting interferometry
photoelastic coefficients, 65; see also strain–optic coefficient; stress–optic coefficient
photoelasticity
color sequence, 98t
compensation, see phase shifting interferometry; fractional fringe order
nonmonochromatic light, 95–6
separating isoclinics and isochromatics, 97–8
whole-field, 72
see also birefringence; holographic interferometry; photoelasticity equations; photoelasticity theory; polariscope optics; reflection photoelasticity; three-dimensional photoelasticity approaches
photoelasticity equations, 67
dark field linear, 70
interpretation of, 69
light field linear, 70
see also interferometric measurement of birefringence, photoelasticity theory
photoelasticity theory, 57
photoelastic material calibration
beam bending test, 113
creep coefficients, 115
disc in compression, 113
laboratory tips, 114
minimum requirements, 103
stress optical coefficient, 107	
tapered specimen, 112
tensile creep test, 110
tension test, 109
time effects, 102
typical result, 107
see also dispersion
photoelastic models, 85
photoelastic model similarity, see model similarity and scaling
photoelastic polariscope, 77
photoelastic stress separation, see stress separation
photoresists, 246
specimen grating, 248
pinhole spatial filter, 223
adjustment of, 225
polariscope calibration, 83
polariscope optics, 77
collimator, 78
light source, 77
monochromatic radiation sources, 78t
polarizers, 78
quarter-wave plates, 79
typical setups, 79–83
polarization, 20
circular, 21, 74
linear, 21
random, 21
projection moire
biomechanical applications, 187, 189–91
coherent beams to create grating, 189
contour changes by, 189–91
contour difference by, 186–91
differential moire, 190–1
in fluid mechanics, 191
fringe interpretation, 186
lateral motion effect, 186
nonparaxial equations, 187–8
optical arrangement, 185
time average, 189
quarter-wave plates, 74
reflection moire, 182
fringe formation, 183
fringe–slope relation, 183
reflection photoelasticity, 141
refraction, 58
absolute index, 58
relative index, 58
relative retardation, 64
fringe order, 64
sensitivity vector, see speckle interferometry
shadow moire, 179
fringe formation, 180
fringe interpretation, 181
slotted apertures
grating frequency multiplication, 239
in grating photography, 235
moire from random patterns, 236
moire rosette, 240
moire sensitivity multiplication, 235
in white light speckle photography, 432
see also speckle photography
spatial filtering, 221
application to moire, 241–65
examples, 222
inverse transform, 221
moire fringe patterns, 234
Subject index

spatial filtering—continued
  optical system, 222
  superimposed gratings, 233
  see also pinhole spatial filter; speckle photography
  speckle correlation interferometry, see
  speckle interferometry
  speckle effect, 395–6
  speckle fields, combinations, see laser speckle
  speckle interferometry
    basic concepts, 441
    creating fringes, 451
    double exposure fringes, 451
    error analysis, 449
    error in displacement measurement, 449
    fringe–displacement relation, 444, 447
    fringe visibility, 451
    and geometric moire, 441
    in-plane displacement, 446
    optical arrangements, 445–8
    optical Fourier processing, 452
    out-of-plane displacement, 444
    phase relationship, 444, 447
    real-time fringes, 451
    recording specklegram, 450
    reference beam, 442
    sensitivity vector, 446
    specklegram as filter mask, 443
    time-average fringes, 451
    see also electronic speckle pattern interferometry; laser speckle; phase shifting interferometry
  speckle photography
    basic idea, 409–12
    calibration procedures, 425
    calibrator, 425–6
    characteristics, 411
    diffraction pattern, 415–19
    dual-aperture technique, 429–31
    Fourier transform, 417, 419–23
    fringe-irradiance distribution, 418
    fringe sensitivity vector, 425
    history, 410
    inverse transform, 423
    limitations, 426–9
    and moire gratings, 414, 429, 431
    pointwise displacement determination, 415–419
    relationship between speckle pairs and
      Fourier transform, 421
    sensitivity, 411
  single aperture method, 412
  single aperture setup, 413
  slotted apertures, 429, 431
  spatial filtering, 419–25
  spatial filtering, physical interpretation, 419–23
  terminology, 411
  two-beam interference in, 429
  whole field displacement fringes, see
  spatial filtering
  Young's fringe–displacement relation, 418
  Young's fringes, 412, 416
  see also laser speckle; speckle interferometry; white light speckle photography
  speckle size, 397–9
  strain–optic coefficient, 66
  stress–optic coefficient, 65, 87, 107
  stress separation
    Dirichlet problem, 125
    finite difference Laplacian, 126
    Laplace equation, 124
    numerical iteration, 125
    oblique incidence, 131
    sample solution by iteration, 127
    series solution, 128
    shear difference, 134
    thickness change method, 129
    see also analogs
  stress trajectories, 90
  three-dimensional moire, see moire with optical processing
  three-dimensional photoelasticity
    approaches, 143
    tuned apertures, see slotted apertures
    TV holography, see electronic speckle pattern interferometry
    two-beam interference, see holography;
      interference, speckle photography
    video holography, see electronic speckle pattern interferometry
    viscoelastic response, 105
    creep compliance, 105
    extension modulus, 105
    optical creep compliance, 107
  wave equation, 17, 18
  wavefronts, 29
  wavelength, 18
### Subject index

<table>
<thead>
<tr>
<th>Term</th>
<th>Page</th>
</tr>
</thead>
<tbody>
<tr>
<td>wavelength units, 19</td>
<td>19</td>
</tr>
<tr>
<td>wave number, 19</td>
<td></td>
</tr>
<tr>
<td>wave propagation in birefringent materials, 60</td>
<td></td>
</tr>
<tr>
<td>white light speckle photography, 431–7</td>
<td></td>
</tr>
<tr>
<td>applications, 433</td>
<td></td>
</tr>
<tr>
<td>atmospheric turbidity effects, 437</td>
<td></td>
</tr>
<tr>
<td>creation of speckle, 432</td>
<td></td>
</tr>
<tr>
<td>fringe formation theory, 433</td>
<td>433</td>
</tr>
<tr>
<td>glacier-flow measurement, 433–7</td>
<td></td>
</tr>
<tr>
<td>Young's fringes in, 435</td>
<td>435</td>
</tr>
<tr>
<td>Young's fringes, 43</td>
<td>43</td>
</tr>
<tr>
<td>interpretation, 45</td>
<td>45</td>
</tr>
<tr>
<td>see also speckle photography, white light speckle photography</td>
<td></td>
</tr>
</tbody>
</table>

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